Notice of R ferenc s Cited	Application/Control No. 10/680,976	Applicant(s)/Patent Under Reexamination HORTZLEZA ET AL.	
	Examiner Hemant M Desai	Art Unit 3721	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,119,865	09-2000	Kawada, Seiichi	206/710
	B	US-6,467,626	10-2002	Misaka, Hitoshi	206/710
	C	US-6,339,254	01-2002	Venkateshwaran et al.	257/686
	D	US-6,335,571	01-2002	Capote et al.	257/787
	E	US-6,710,454	03-2004	Boon, Suan Jeung	257/777
	F	US-6,222,259	04-2001	Park et al.	257/690
	G	US-6,344,664	02-2002	Trezza et al.	257/82
	H	US-6,352,878	03-2002	Mostafazadeh et al.	438/106
	I	US-6,533,123	03-2003	Nakamura et al.	206/710
	J	US-4,886,162	12-1989	Ambrogio, Sala	206/710
	K	US-4,787,508	11-1988	Wu et al.	206/445
	L	US-4,203,127	05-1980	Tegge, Jr., Bruce R.	206/710
	M	US-6,817,161	11-2004	Wu et al.	53/449

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.